Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/630,683	CHEN, YI-CHEN
Examiner	Art Unit
Navneet Sonia Khaira	3754

	SEARCHED				
Class	Subclass	Date	Examiner		
222	129,181.1, 153.01	4/4/2005	NK		
222	153.03	4/4/2005	NK		
222	160,173	4/4/2005	NK		
222	493	4/4/2005	NK		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH	H STRATEGY	()
	DATE	EXMR
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